Optoelectronics and Energy Devices Require Fiber Optic Spectrometer for Film Thickness Measurement

Basic Information

Place of Origin: CHINA
Brand Name: JINSP
Certification: ISO9001
Model Number: SR100Q
Minimum Order Quantity: 1

• Price: Negotiable

Packaging Details: International Shipping Pakcage

Delivery Time: 90-120 working days
 Payment Terms: T/T, Western Union
 Supply Ability: 100PCS/90-120 days



Product Specification

Spectrual Range: 200nm - 1100nmEffective Pixels: 1024*122

• Qutuam Efficiency: QE92%peak@650nm, 83%@232nm

• SNR: 1000:1



PJINSP

More Images



92% High Quantum Spectrometer for Film Thickness Measurement

As thin films become ubiquitous in optoelectronics and energy devices, thickness measurement grows in importance. Photoelectric solutions outperform traditional methods by eliminating physical contact and preventing damage. Cutting-edge systems employing adaptive algorithms are transforming quality assurance processes across multiple sectors.

Product Parameters:

Chip Type	Back-illuminated TE-cooled Hamamatsu S7031		
Effective Pixel	1024*122		
Pixel Size	24*24μm		
Sensing Area	24.576*2.928mm		
Optical Design	F/4 cross-type		
Numerical Aperture	0.13		
Focal Length	100mm		
Entrance Slit Width	10μm,25μm,50μm,100μm,200μm (customizable)		
Fiber Interface	SMA905,free space		
Integration Time	8ms-3600s		
Data Output Interface	USB3.0,RS232,RS485,20pin connector		
ADC Bit Depth	16-bit		
Power Supply	5V		
Operating Current	<3.5A		
Operating Temperature	10 ~40		
Storage Temperature	-20 ~60		
Operating Humidity	<90%RH (no condensation)		
Dimensions	180mm*120mm*50mm		
Weight	1.2kg		
	Effective Pixel Pixel Size Sensing Area Optical Design Numerical Aperture Focal Length Entrance Slit Width Fiber Interface Integration Time Data Output Interface ADC Bit Depth Power Supply Operating Current Operating Temperature Storage Temperature Operating Humidity Dimensions		

List of Product Models:

Model	Spectral Range(nm)	Resolution(nm)	Slit(µm)
		6.8	200
SR100Q-G21	200~950	2.2	50
SR100Q-G22	350~1100	1.5	25
		1.0	10
SR100Q-G23	200~775	1.6	50
SR100Q-G24 350~925	050 005	1.0	25
	350~925	0.7	10
SR100Q-G25	532~690(4400cm-1*)*	13cm-1	50
SR100Q-G26	638~800(3200cm-1)*	10cm-1	25
SR100Q-G27	785~1050(3200cm-1)*	11cm-1	50

Note: The*are primarily designed for Raman applications, with the corresponding Raman.

Technical Characteristics:

High quantum efficiency, 92%peak@650nm, 83%@232nm

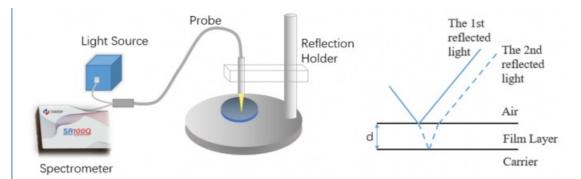
High SNR: Ultra-low dark noise under long integration time, SNR is as high as 1000:1

Noise-free clear processing of weak signal in long exposure, strong adaption to environment

Low-noise and high-speed circuit: USB3.0

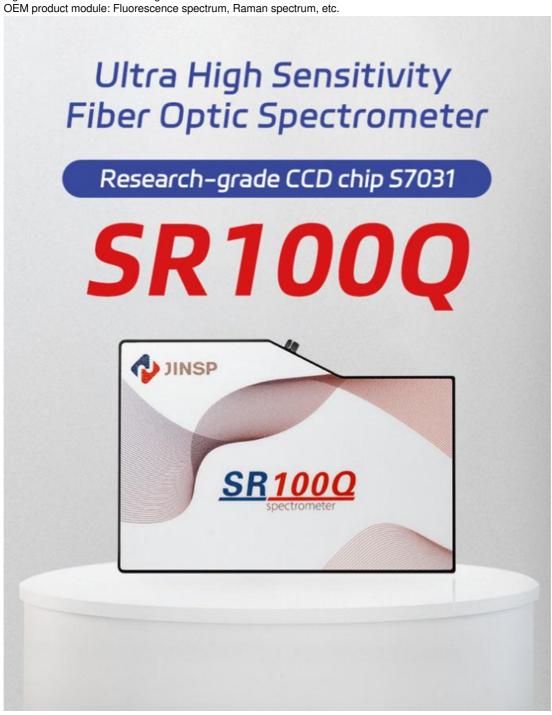
Measurement Method:

The optical fiber probe delivers light to the film, producing reflections at the air-film and film-substrate boundaries. The spectrometer captures the interference pattern formed by these beams, from which thickness (d) is derived via the extremum method (using θ , n, and spectral features). Fringe spacing varies with thickness (inversely with wavelength), necessitating tailored spectral parameters for accuracy.

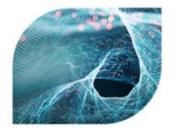


Typical Applications:

Detect absorption, transmittance and reflection Spectrum
Light source and laser wavelength characterization
OFM product module: Fluorescence spectrum, Raman spectrum, etc.



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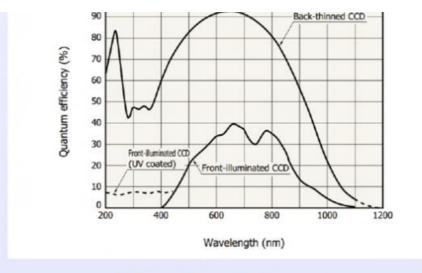


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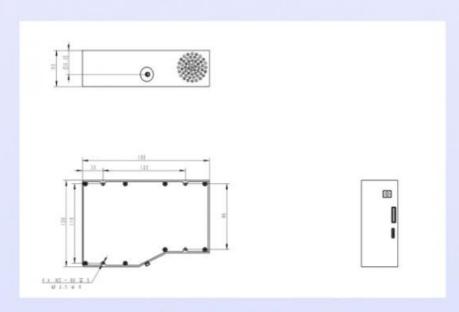


OEM product module: Fluorescence spectrum, Raman spectrum, etc.

(Typ. Ta=25 °C



CCD Quantum Efficiency Curve



Installation dimension drawing

Company Introduction:

JINSP Company Limited, abbreviated as "JINSP", is a professional supplier with over 17 years of experience in spectral detection technology products, including Raman, FT-IR, LIBS technologies, etc. After 17 years of technology accumulation, the company's core key technologies have reached the international leading position at the level, and the cumulative number of patent applications exceeded 200.

In addition to its main headquarters located in the bustling city of Beijing, JINSP has established a fully owned subsidiary manufacturing facility situated in the province of Jiangsu, China.

JINSP Company received ISO9001:2015, ISO14001:2015, and ISO45001:2018 certifications. JINSP can provide required certifications, such as certification by the Ministry of Public Security or National Institute of Metrology, Environmental Level Certification, IP Level Certification, CE Certification, Transport Identification Report, EU ECAC certification, German ICT Security Testing, etc.

Company Profile









Exhibition









Certifications







FAQ

A1:We will send you manual and guide vedio in English, it can teach you how to operate the spectrometer. Also our technicians will offer professional tecnical opearation meetings.

Q2: Can your offer a operation traning?

A2: Your technicians can come to our factory for a training. Jinsp engineers can go to your place for local support (installation, training, debugging, maintenance).

Q3: What's your website?

A3:You can visit:www.jinsptech.com

Q4: What about your quality assurance?

A4: We have a quality inspection team. All goods will go through quality inspection before shipment. We can send you pictures for inspection.



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